

Notice of References Cited	Application/Control No. 09/721,015	Applicant(s)/Patent Under Reexamination WONG ET AL.	
	Examiner ANH H DO	Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,199,788	04-1980	Tsujimura, Katsuhito	348/594
	B	US-4,176,379	11-1979	Wessler et al.	358/409
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 0282734	02-1988	Europe	Takagi et al.	H01L 27/06
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NON-PATENT DOCUMENTS

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	U	Epp et al., "Generalized Scattering Matrices for Unit Cell Characterization of Grid Amplifiers and Device De-Embedding", IEEE Vol. 2, June 1995, pps. 1288-1291.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.